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**CLAIMS** 

What is claimed is:

1. An eddy current probe for detecting defects in an electrically conductive specimen

under test (SUT), the eddy current probe comprising:

a. at least one excitation coil having a cross-section disposed within a

common plane, the at least one excitation coil having a symmetry axis within the

common plane, wherein the at least one excitation coil creates a magnetic field

and eddy currents into SUT; and

b. at least one magnetic senor operable to be positioned on the symmetry axis

of the at least one excitation coil and having a sensitive axis operable to be

disposed within the common plane perpendicular to the symmetry axis of the at

least one excitation coil.

2. The eddy current probe according to claim 1, wherein the at least one excitation coil

comprises a substantially rectangular cross-section.

3. The eddy current probe according to claim 1, wherein the at least one excitation coil

comprises a pair of substantially identical excitation coils symmetrically disposed

about the symmetry axis.

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4. The eddy current probe according to claim 3, wherein each excitation coil of the pair

of substantially identical excitation coils comprises a substantially rectangular cross-

section.

5. The eddy current probe according to claim 3, wherein the pair of substantially

identical excitation coils are operable to be interconnected such that when an electric

current is passed through the pair of substantially identical excitation coils, each

excitation coil of the pair of substantially identical excitation coils create a magnetic

field in the same direction.

6. The eddy current probe according to claim 3, further comprising a third excitation

coil configured to be located between the pair of substantially identical excitation

coils, wherein the three excitation coils are operable to be interconnected such that

when an electric current is passed through the three excitation coils, the magnetic

field created by the third excitation coil and the magnetic field created by the pair of

substantially identical excitation coils are in opposite directions.

7. The eddy current probe according to claim 6, wherein each of the three excitation

coils comprises a substantially rectangular cross-section.

8. The eddy current probe according to claim 3, wherein the pair of substantially

identical excitation coils is operable to be configured such that they intersect.

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9. The eddy current probe according to claim 1, wherein the at least one excitation coil comprises a flat coil having at least one layer.

10. The eddy current probe according to claim 9, wherein the flat coil comprises multiple

layers.

11. The eddy current probe according to claim 1, wherein the at least one excitation coil

comprises:

a. a ribbon cable comprising a plurality of parallel insulated wires and

having two ends;

b. a pair of electrical connectors, each electrical connector attached to the

ribbon cable; and

c. a plurality of jumper wires operable to be attached to the electrical

connectors to form the at least one excitation coil.

12. The eddy current probe according to claim 1, wherein the at least one excitation coil

is patterned on an electrically insulated substrate.

13. The eddy current probe according to claim 1, wherein the at least one excitation coil

is patterned from a metallic sheet.

14. The eddy current probe according to claim 1, wherein the at least one excitation coil

comprises an electrically conductive foil.

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15. The eddy current probe according to claim 1, wherein the set of excitation coils is patterned from a metallic sheet without an insulating substrate.

- 16. The eddy current probe according to claim 1, wherein the at least one magnetic sensor comprises a plurality of substantially identical magnetic sensors.
- 17. The eddy current probe according to claim 16, wherein the plurality of substantially identical magnetic sensors are operable to be disposed in a linear array.
- 18. The eddy current probe according to claim 1, wherein the at least one magnetic sensor comprises at least one magnetoresistive sensor.
- 19. The eddy current probe according to claim 18, wherein the magnetoresistive sensor comprises at least one giant magnetoresistive sensor, anisotropic magnetoresistive sensor, or spin-dependent tunneling sensor.
- 20. The eddy current probe according to claim 1, wherein the at least one magnetic sensor comprises at least one Hall-effect sensor

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21. An eddy current testing system for detecting and monitoring defects in an electrically

conductive specimen under test (SUT), the eddy current testing system comprising:

a. an eddy current probe according to claim 1;

b. an AC power supply electrically connected to the at least one excitation

coil of the eddy current probe;

c. an amplifier electrically connected to the at least one magnetic sensor of

the eddy current probe;

d. an amplitude and phase detector capable of receiving the signal from the

amplifier.

22. The eddy current system according to claim 21, further comprising a data recorder in

communication with the detector.

23. The eddy current system according to claim 21, further comprising a display in

communication with the detector.

24. The eddy current system according to claim 21, wherein the amplitude and phase

detector comprises a lock-in amplifier.

25. The eddy current system according to claim 21, wherein the amplitude and phase

detector comprises program code stored on a computer readable media.

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26. The eddy current system according to claim 21, wherein the eddy current probe

comprises a plurality of magnetic sensors and wherein the eddy current testing system

is operable to compute the sum of or difference between a plurality of output signals

from the plurality of magnetic sensors.

27. An eddy current probe for detecting defects within a specimen under test (SUT)

comprising:

a. a flat excitation coil of rectangular cross-section having an axis of

symmetry within a plane of the cross-section; and

b. a linear array of magnetoresistive sensors disposed at the axis of symmetry

of the flat excitation coil, each magnetoresistive sensor in the array having a

sensitive axis operable to be disposed perpendicular to the axis of symmetry of

the excitation coil.

28. A method for detecting defects within a specimen under test (SUT) comprising

scanning an eddy current probe according to claim 1 above the top surface of the

SUT, wherein the cross-section of the at least one excitation coil of the eddy current

probe is coplanar with the top surface of the SUT.

29. A method for detecting cracks in a specimen under test (SUT) having at least one row

of fastener holes, wherein each row of fastener holes has a symmetry axis that

intersects the centers of all holes in the row, comprising scanning the eddy current

probe according to claim 1 above the top surface of the SUT along the symmetry axis

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of the fastener holes such that the at least one magnetic sensor passes along the

symmetry axis of the row of fastener holes.

30. An eddy current probe comprising:

a. a flat excitation coil having a substantially rectangular cross-section and

having an axis of symmetry within the plane of the cross-section;

b. two magnetoresistive sensors operable to be disposed at the axis of

symmetry of the excitation coil, each magnetoresistive sensor having a sensitive

axis operable to be disposed perpendicular to the axis of symmetry of the

excitation coil, wherein the two magnetoresistive sensors are operable to be

connected in a gradiometer configuration.

31. A method for detecting cracks in a specimen under test (SUT) having at least one row

of fastener holes, wherein each row of fastener holes has a symmetry axis that

intersects the centers of all holes in the row, comprising:

a. configuring the eddy current probe according to claim 30 such that the

distance between the two sensors is substantially the same as the distance between

the centers of two adjacent fastener holes; and

b. scanning the eddy current probe according to claim 30 above the top

surface of the SUT such that the two magnetoresistive sensors pass along the

symmetry axis of the row of fastener holes.

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32. An eddy current probe for detecting defects in an electrically conductive specimen

under test (SUT), the eddy current probe comprising:

a. a pair of substantially identical excitation coils having substantially

rectangular cross-sections operable to be disposed within a common plane, the

pair of excitation coils having a first symmetry axis and a second symmetry axis

orthogonal to the first symmetry axis within the common plane, wherein the pair

of excitation coils are interconnected such that they create magnetic field and

eddy currents into SUT in opposite directions if an electric current is passed

through the pair of excitation coils; and

b. at least one magnetic sensor operable to be positioned on the second

symmetry axis of the pair of excitation coils and having a sensitive axis operable

to be disposed within the common plane perpendicular to the second symmetry

axis of the pair of excitation coils.

33. The eddy current according to claim 32, wherein the pair of excitation coils intersect.

34. The eddy current probe according to claim 32, wherein the pair of excitation coils

comprises a flat coil having at least one layer.

35. The eddy current probe according to claim 32, wherein the pair of excitation coils

comprises a flat coil having multiple layers.

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36. The eddy current probe according to claim 32, wherein the pair of excitation coils

comprises:

a. a ribbon cable comprising a plurality of parallel insulated wires and having two

ends;

b. a pair of electrical connectors, each electrical connector attached to the ribbon

cable; and

c. a plurality of jumper wires operable to be attached to the electrical connectors to

form the at least one excitation coil.

37. The eddy current probe according to claim 32, wherein the at least one magnetic

sensor comprises a plurality of substantially identical magnetic sensors.

38. The eddy current probe according to claim 32, wherein the plurality of substantially

identical magnetic sensors are operable to be disposed in a linear array.

39. The eddy current probe according to claim 32, wherein the at least one magnetic

sensor comprises at least one pair of substantially identical magnetic sensors

symmetrically disposed about the first symmetry axis.

40. The eddy current probe according to claim 32, wherein the at least one magnetic

sensor comprises at least one magnetoresistive sensor.

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41. The eddy current probe according to claim 32, wherein the at least one magnetic

sensor comprises at least one Hall-effect sensor.

42. An eddy current testing system for detecting and monitoring defects in an electrically

conductive specimen under test (SUT), the eddy current testing system comprising:

a. an eddy current probe according to claim 32;

b. an AC power supply electrically connected to the pair of excitation coils of the

eddy current probe;

c. an amplifier electrically connected to the at least one magnetic sensor of the eddy

current probe; and

d. an amplitude and phase detector capable of receiving the signal from the

amplifier.

43. The eddy current system according to claim 41, further comprising a data recorder in

communication with the detector.

44. The eddy current system according to claim 41, further comprising a display in

communication with the detector.

45. The eddy current system according to claim 41, wherein the amplitude and phase

detector comprises a lock-in amplifier.

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46. The eddy current system according to claim 41, wherein the amplitude and phase

detector comprises program code stored on a computer readable media.

47. The eddy current system according to claim 41, wherein the eddy current probe

comprises a plurality of magnetic sensors and wherein the eddy current testing system

is operable to compute the sum of or difference between a plurality of output signals

from the plurality of magnetic sensors.

48. An eddy current probe for detecting defects within a specimen under test (SUT)

comprising:

a. a pair of flat excitation coils having a rectangular cross-section and having a first

symmetry axis and a second symmetry axis orthogonal to the first symmetry axis

within the plane of the cross-section; and

b. a linear array of magnetoresistive sensors disposed at the second symmetry axis of

the pair of excitation coils, each magnetoresistive sensor in the array having a

sensitive axis disposed within the plane of the cross-section, wherein the sensitive

axis is perpendicular to the second symmetry axis of the pair of excitation coils.

49. An eddy current probe for detecting cracks in a specimen under testing (SUT) having

a row of fastener holes, wherein the row of fastener holes has a symmetry axis that

intersects the centers of all holes in the row, wherein the eddy current probe

comprises:

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a. a pair of flat excitation coils having rectangular cross-sections and having a first

symmetry axis and a second symmetry axis orthogonal to the first symmetry axis

within the plane of the cross-section;

b. a magnetoresistive sensor disposed at the intersection of the first symmetry axis

and the second symmetry axis of the pair of excitation coils, the magnetoresistive

sensor having a sensitive axis disposed within the plane of the cross-section, wherein

the sensitive axis of the magnetoresisitve sensor is perpendicular to the second

symmetry axis of the excitation coil.

50. A method for detecting defects within a specimen under test (SUT) comprising

scanning an eddy current probe according to claim 32 above the top surface of the

SUT, wherein the cross-section of the pair of excitation coils of the eddy current

probe is coplanar with the top surface of the SUT.

51. A method for detecting cracks in a specimen under test (SUT) having at least one row

of fastener holes, wherein each row of fastener holes has a symmetry axis that

intersects the centers of all holes in the row, comprising scanning the eddy current

probe according to claim 32 above the top surface of the SUT along the symmetry

axis of the fastener holes such that the first symmetry axis of the excitation coils

substantially coincides with the symmetry axis of the row of fastener holes.